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# GLAST LAT tracker signal simulation and trigger timing study

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(presented by F. Loparco)

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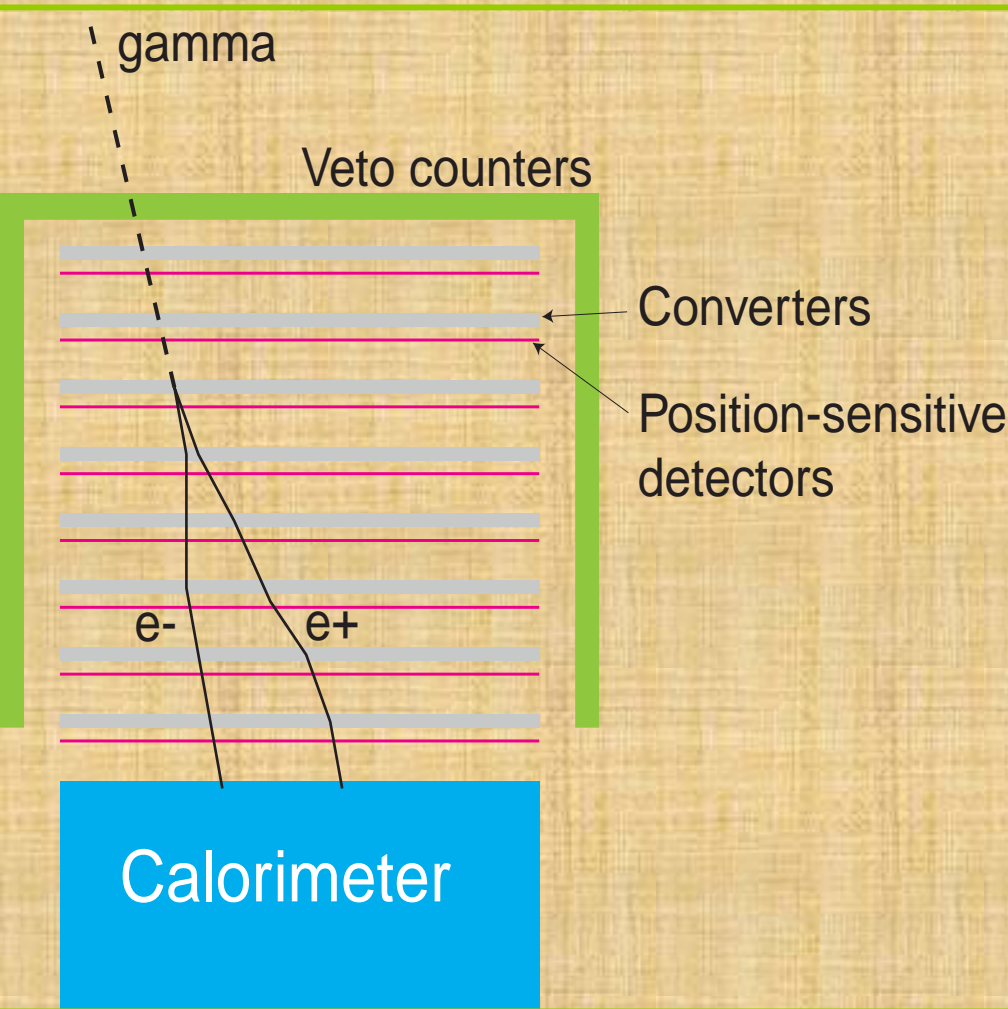
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# OUTLINE

- The *Glast* LAT tracker system
- The digital signal read-out simulation
- Timing study: hit capture efficiency
- Conclusions

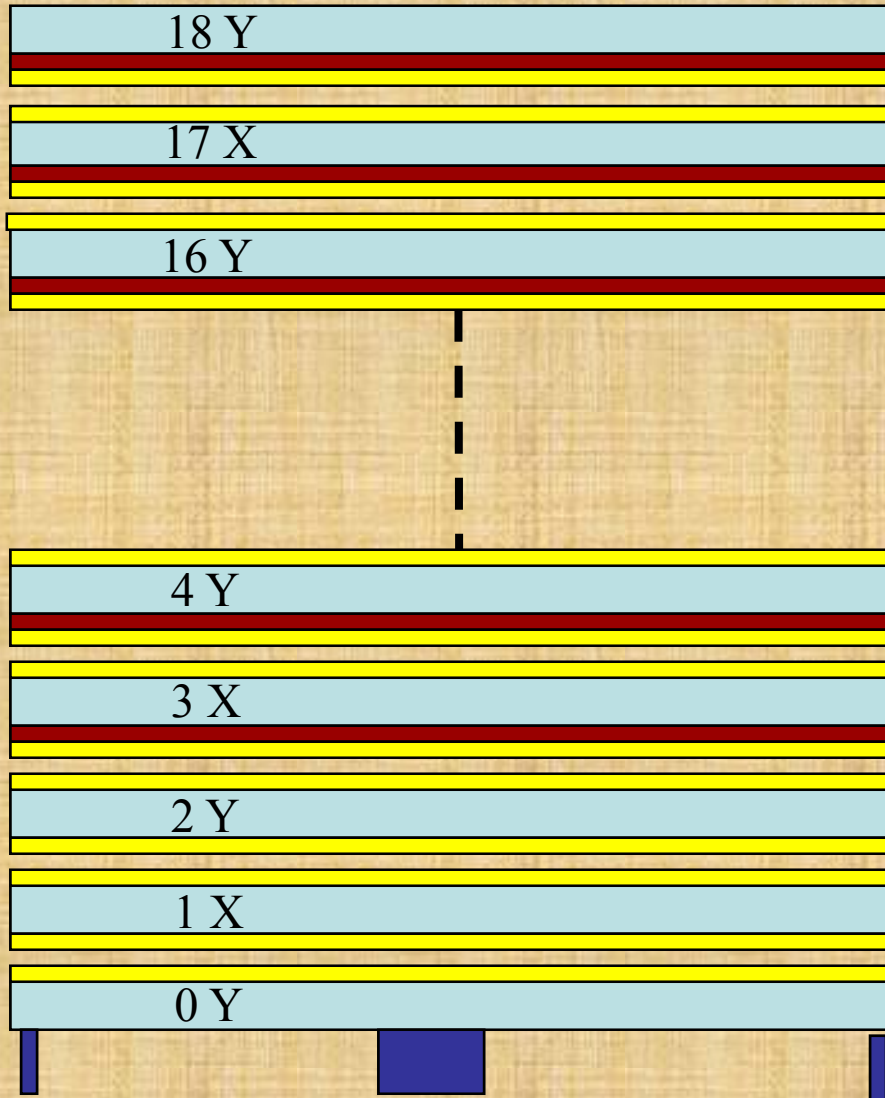
# LAT Tracker system

$$\gamma \rightarrow e^+ e^-$$



- **Si-strip Tracker (TKR)**  
19 tracking planes. Single-sided silicon strip detectors + W.  
Measure the photon direction;  
gamma ID.
- **CsI Calorimeter (CAL)**  
Array of CsI(Tl) crystals  
Measure the photon energy;  
image the shower.
- **Anticoincidence Detector (ACD)**  
Plastic scintillator tiles.  
Reject background of charged  
cosmic rays; segmentation  
removes self-veto effects at  
high energy.

# Tracker Tray Configuration



➤ 16 "towers" (36cm × 36cm)

➤ 83m<sup>2</sup> of Si

➤ 11500 SSDs, 1M channels

➤ 18 *x,y* layers per tower

➤ 19 "trays"

➤ 12 with 3%  $X_0$  ("Front")

➤ 4 with 18%  $X_0$  ("Back")

➤ 3 no converter

➤ Total length: 1.5  $X_0$

➤ SSDs (Silicon Strip Detectors)

➤ Wafer thickness 400  $\mu\text{m}$

➤ Wafer Area 8.96 × 8.96 cm<sup>2</sup>

➤ Strip pitch 228  $\mu\text{m}$

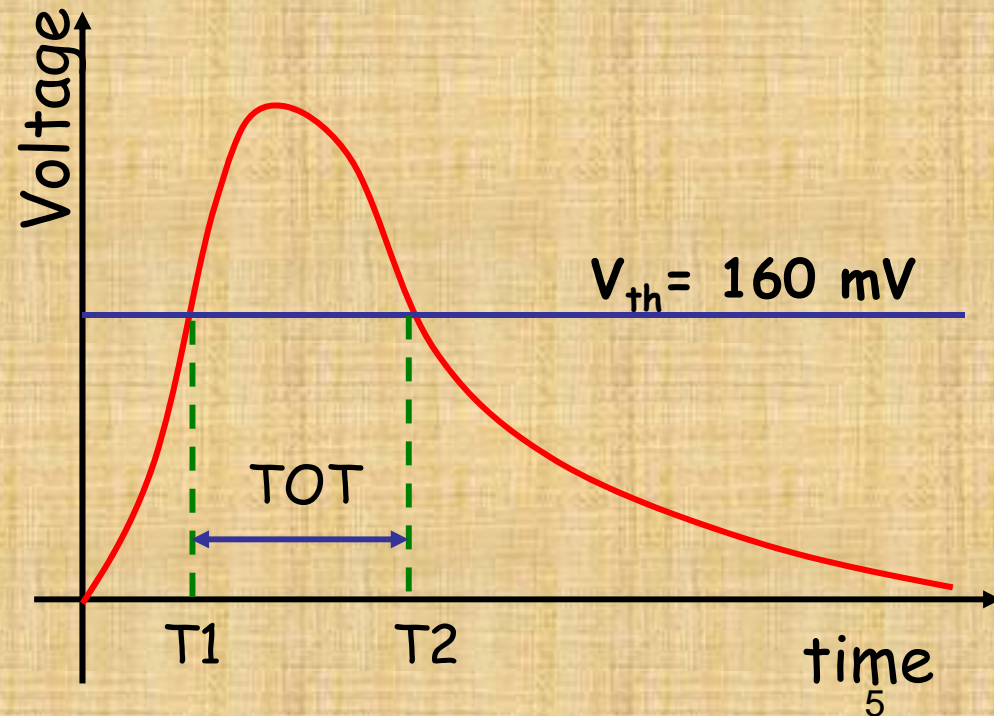
➤ Strip width 64  $\mu\text{m}$

# LAT Tracker digital signal read-out

- The electronics chain consists of charge preamplifier, shaper and comparator
- The front-end electronics has been designed to evaluate the charge collected by the strips from the Time-over-Threshold (ToT).

- **Digital Output:**
  - IDs of fired strips
  - ToT per layer (i.e. ORing per layer)

$$\text{ToT} \approx 1.6 \mu\text{s}/\text{fC}$$



**G4 LAT simulation**  
(see previous talk)



**INPUT:**  
• Input and exit point  
• Energy loss



**Clusters generation**



**CLUSTER PROPAGATION:**  
• e-h motion  
• Induced current signal



**ELECTRONICS:**  
• NOISE  
• Voltage signal evaluation



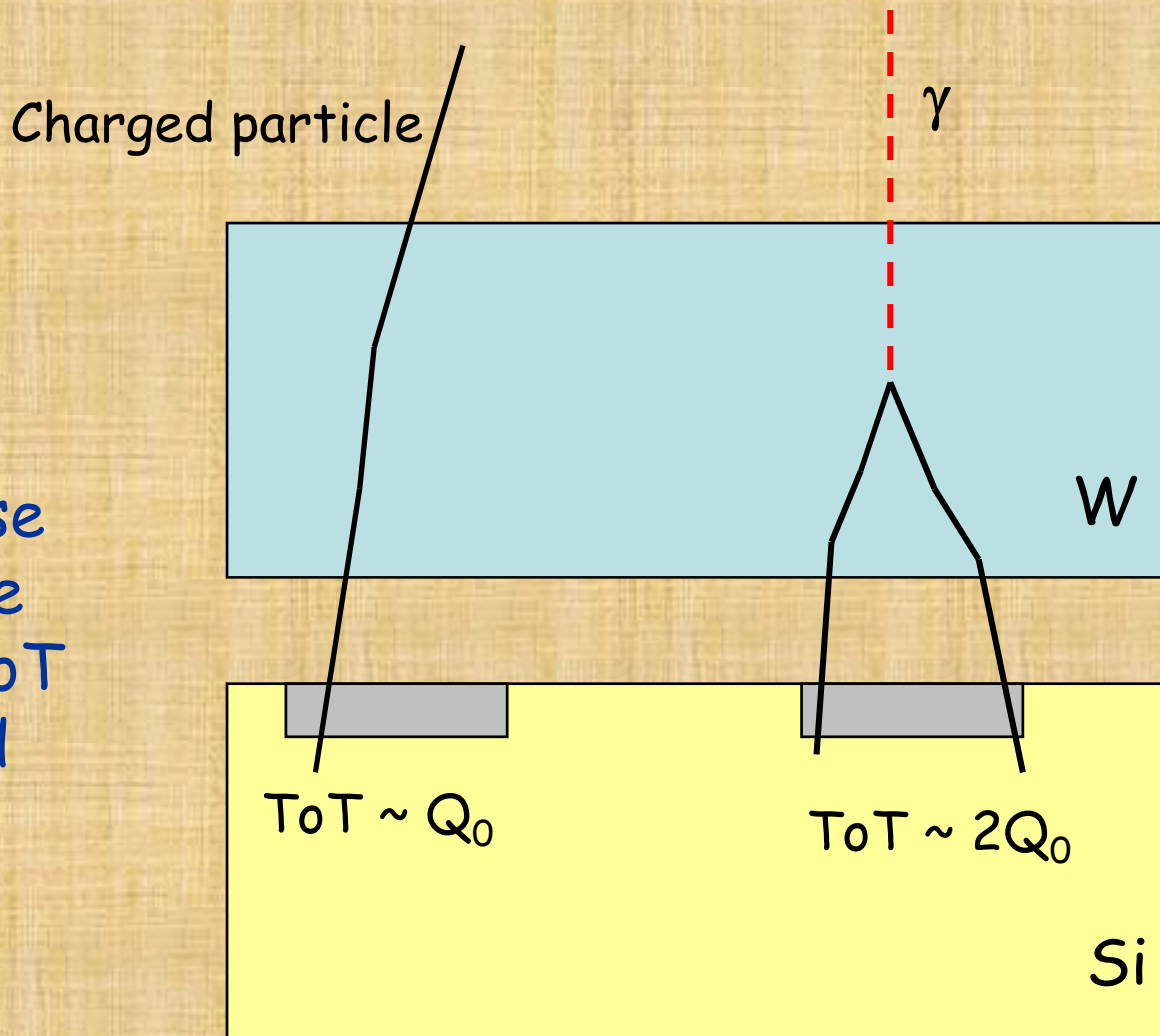
**OUTPUT:**  
• Fired strips list, per layer  
• TOT per layer

# TKR DIGIT

## simulation chain:

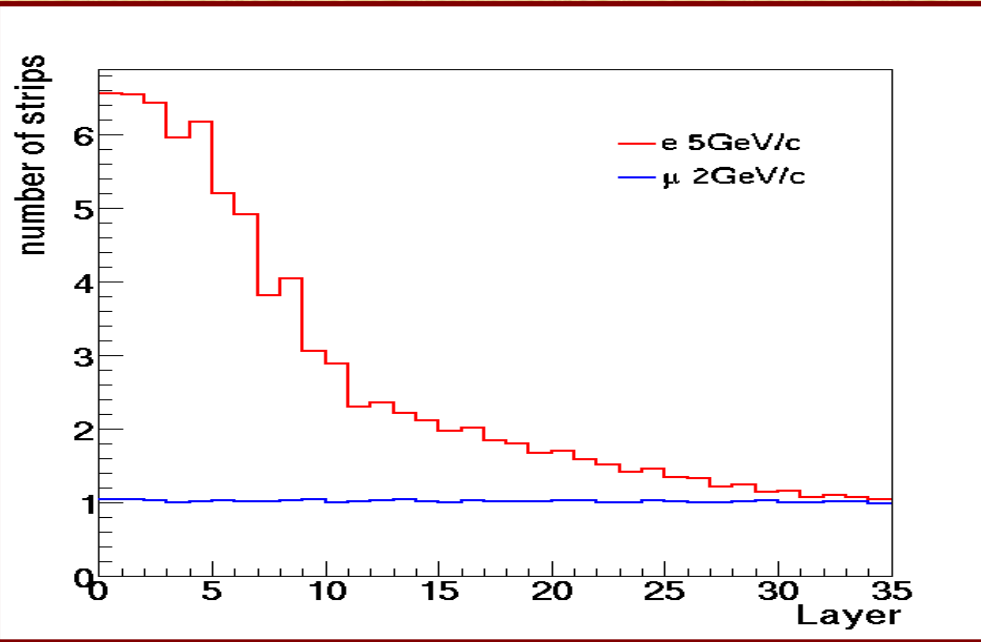
we use a simplified version of  
a full SSD signal simulation  
(see F.Loparco talk)

# ToT for $\gamma$ and charged particles



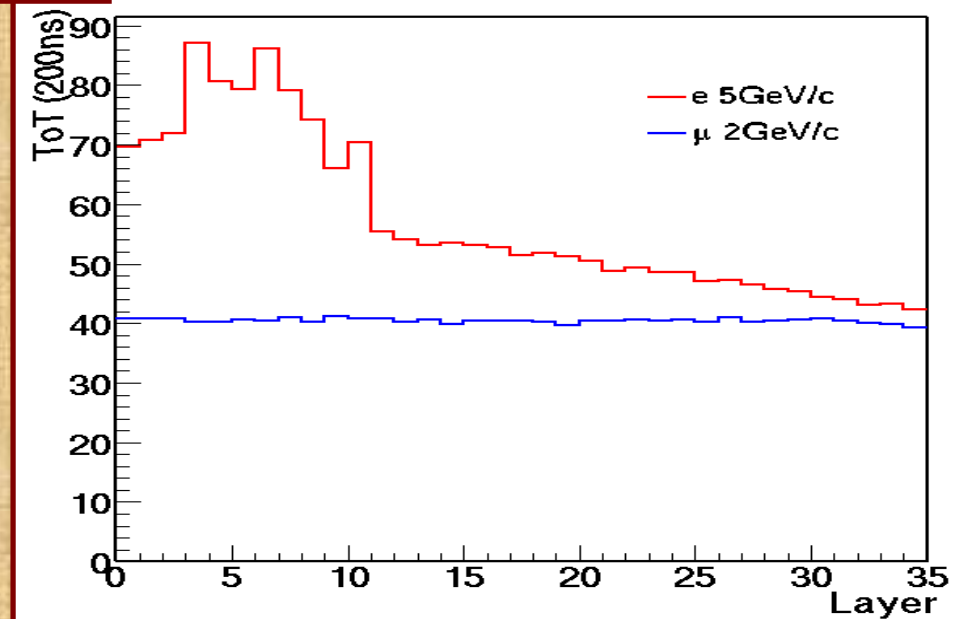
If electron and positron from  $\gamma$  conversion release charge on a single strip, a double ToT value is expected

# Multiplicity and ToT for layers

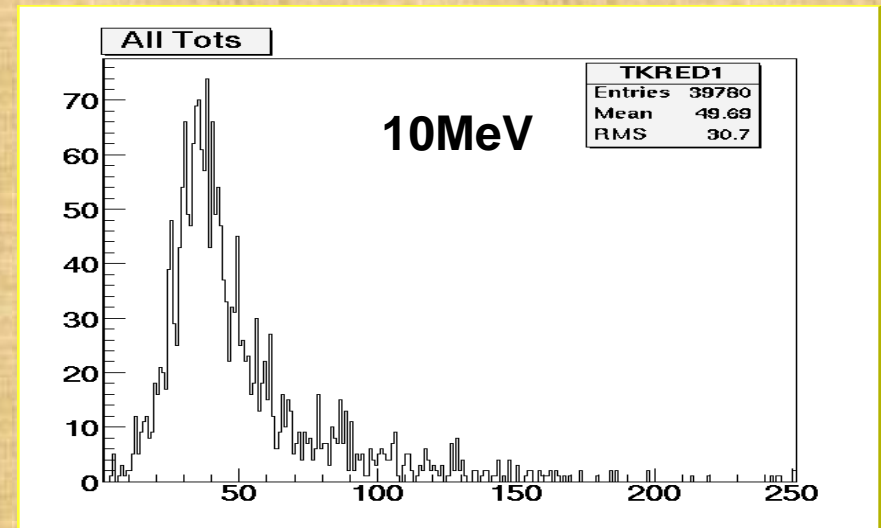
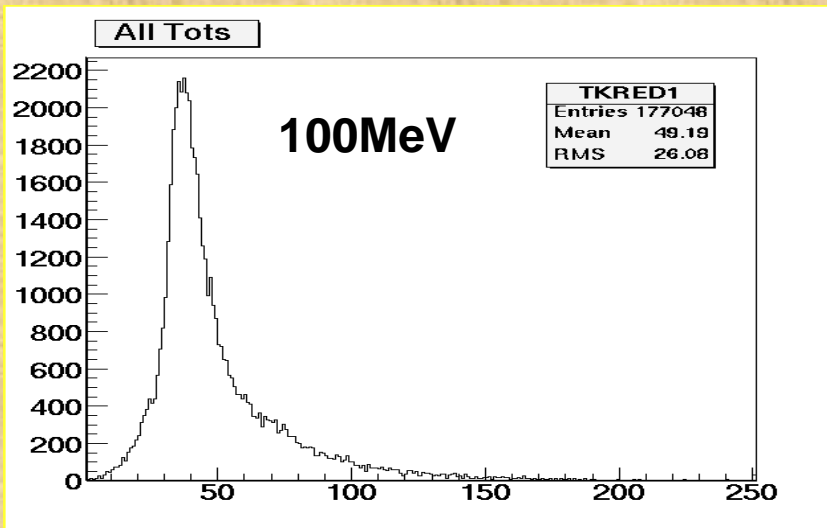
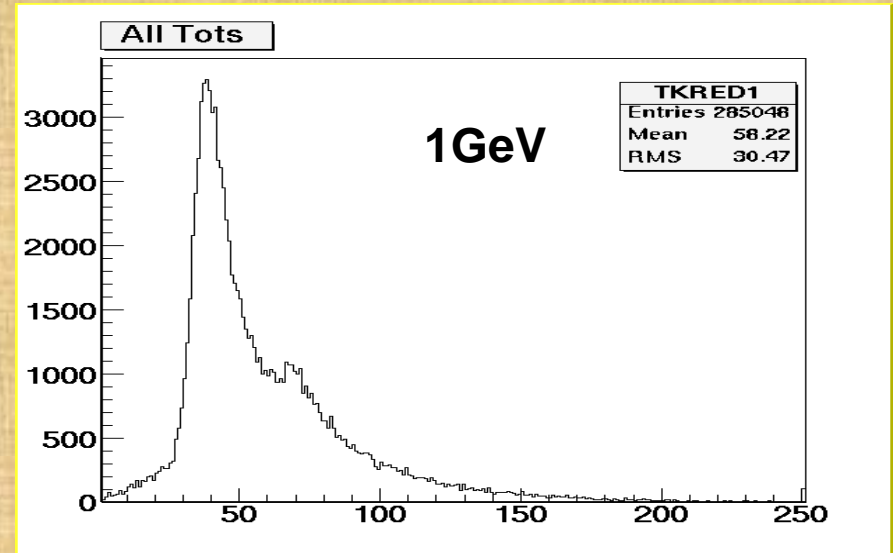
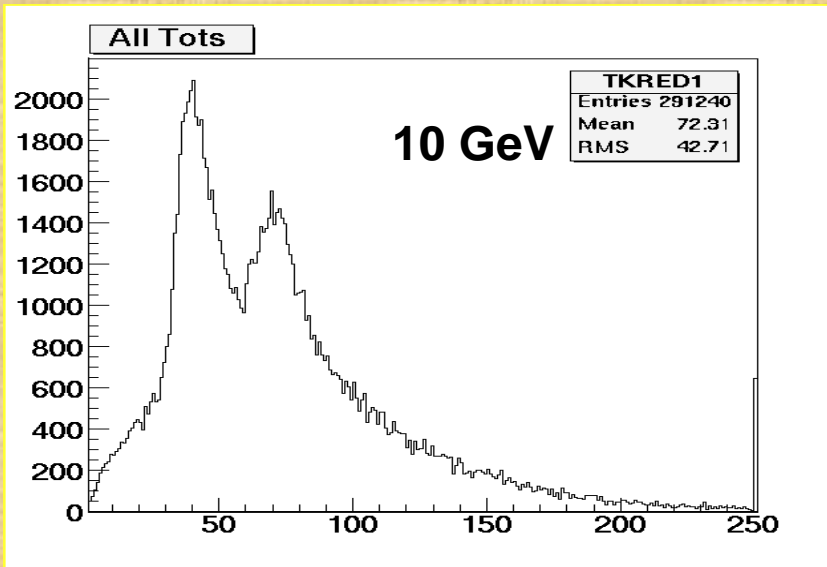


Average strip  
multiplicity per layer

Average ToT per layer

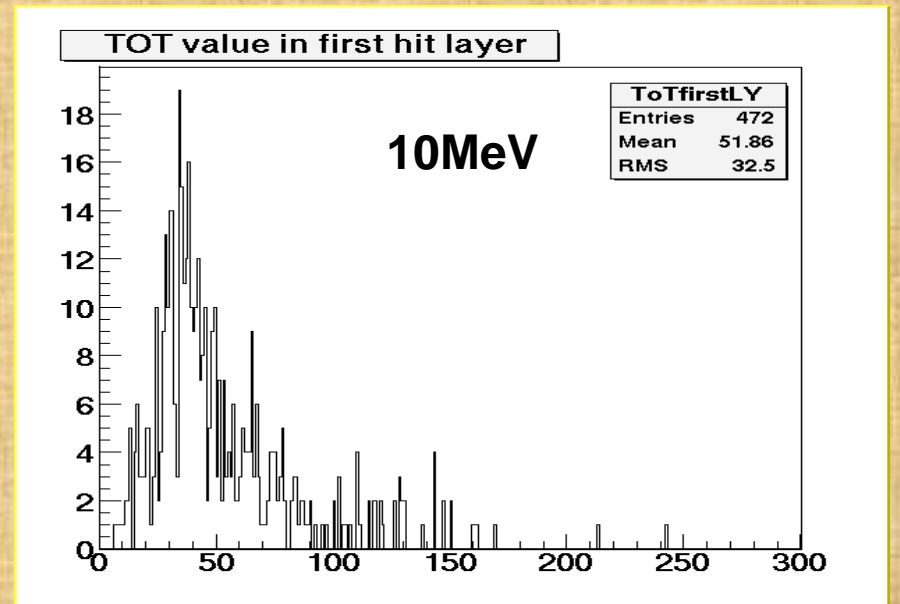
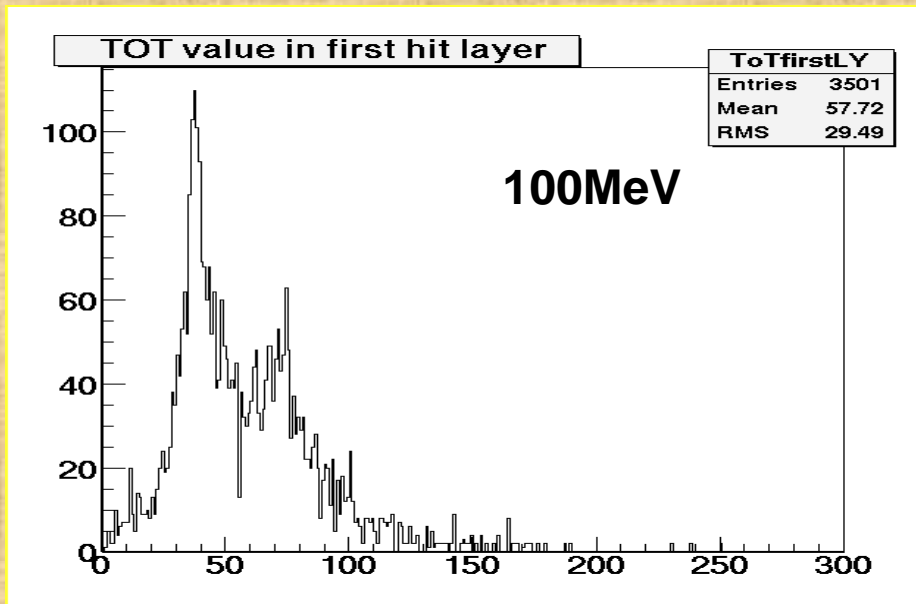
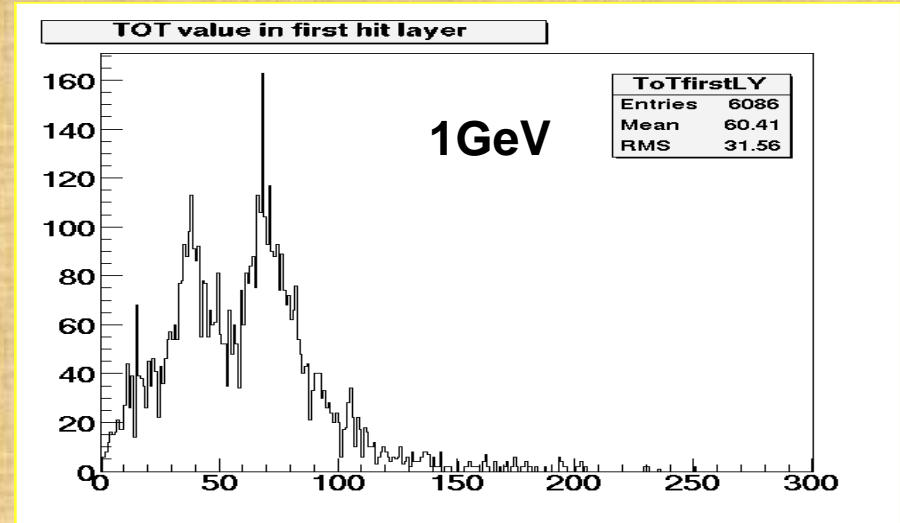
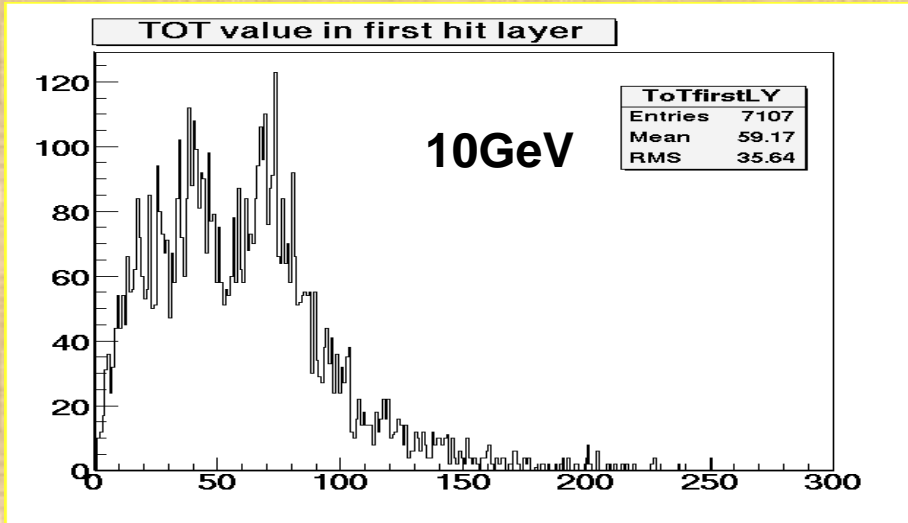


# ToT distribution for $\gamma$ -rays



ToT (200ns step)

# ToT distribution for $\gamma$ -rays



ToT (200ns step)

# TKR L1 trigger simulation

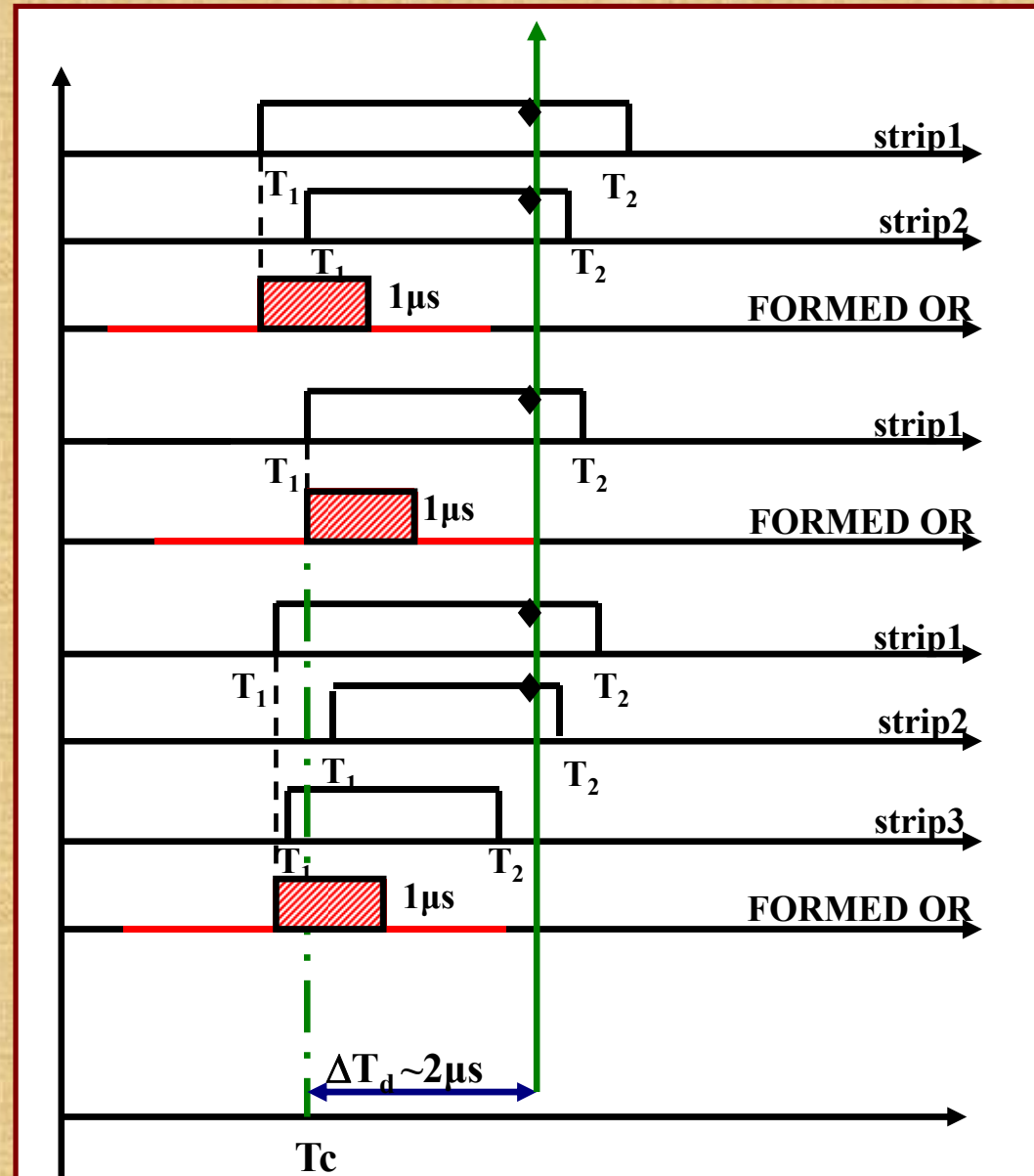
## L1 trigger



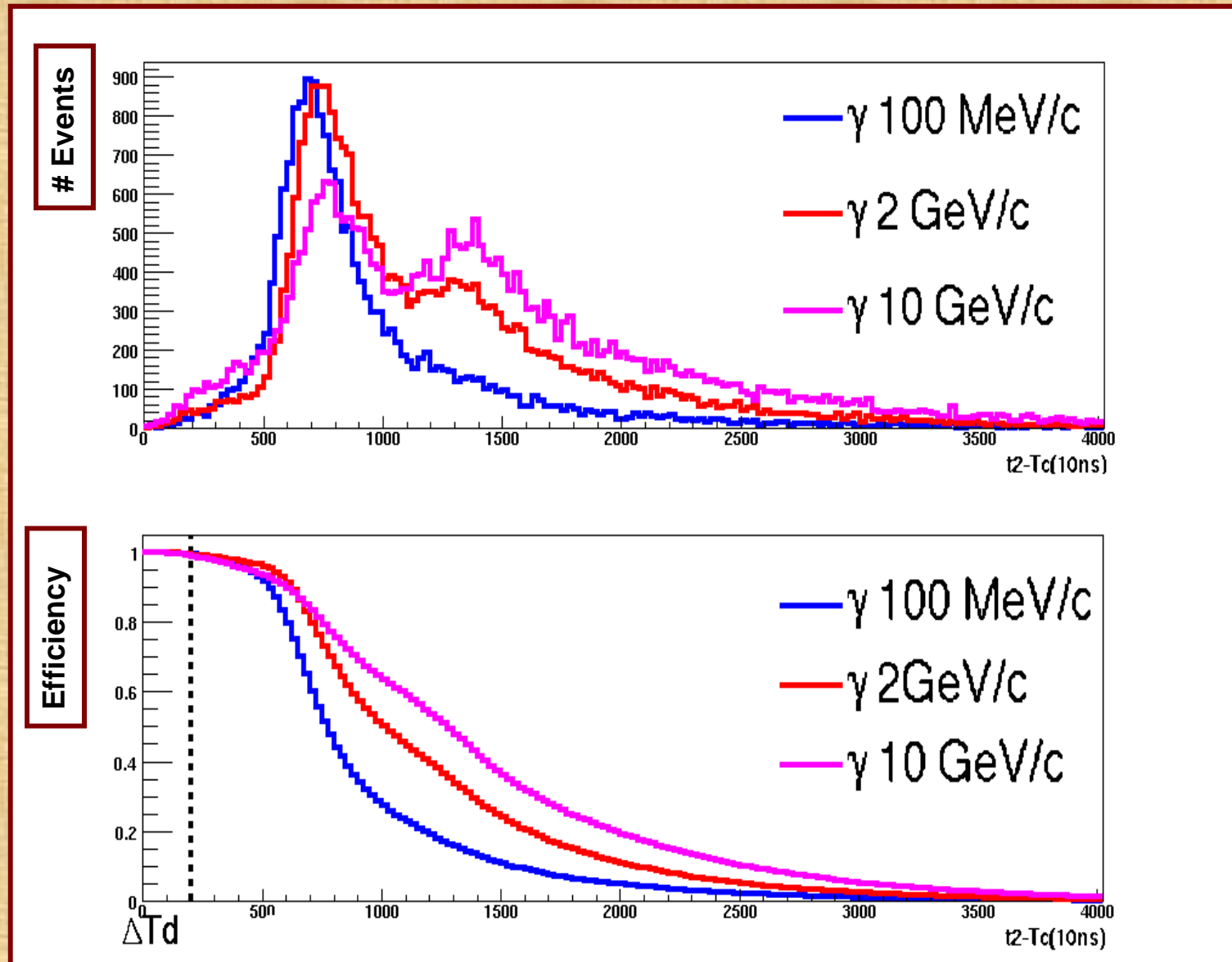
- 6-fold coincidence  
(first 3-x and 3-y hit layers)
- $T_c$  is the time coincidence



The strip is "captured" if  
 $T_2 - T_c > \Delta T_d (2\mu s)$   
where  $\Delta T_d$  is the trigger  
acknowledgement



# Hit capture efficiency ( $V_{th} = 160\text{mV}$ )



# Events

Efficiency

~ 100%  
captured  
"hit"

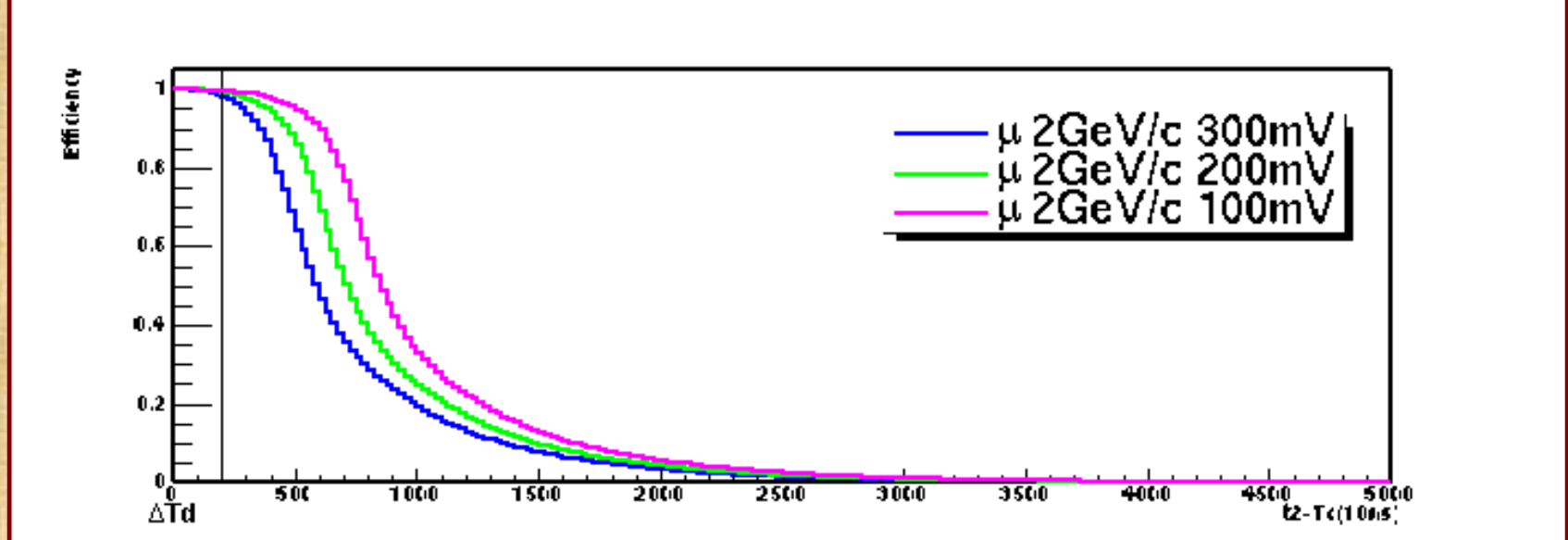
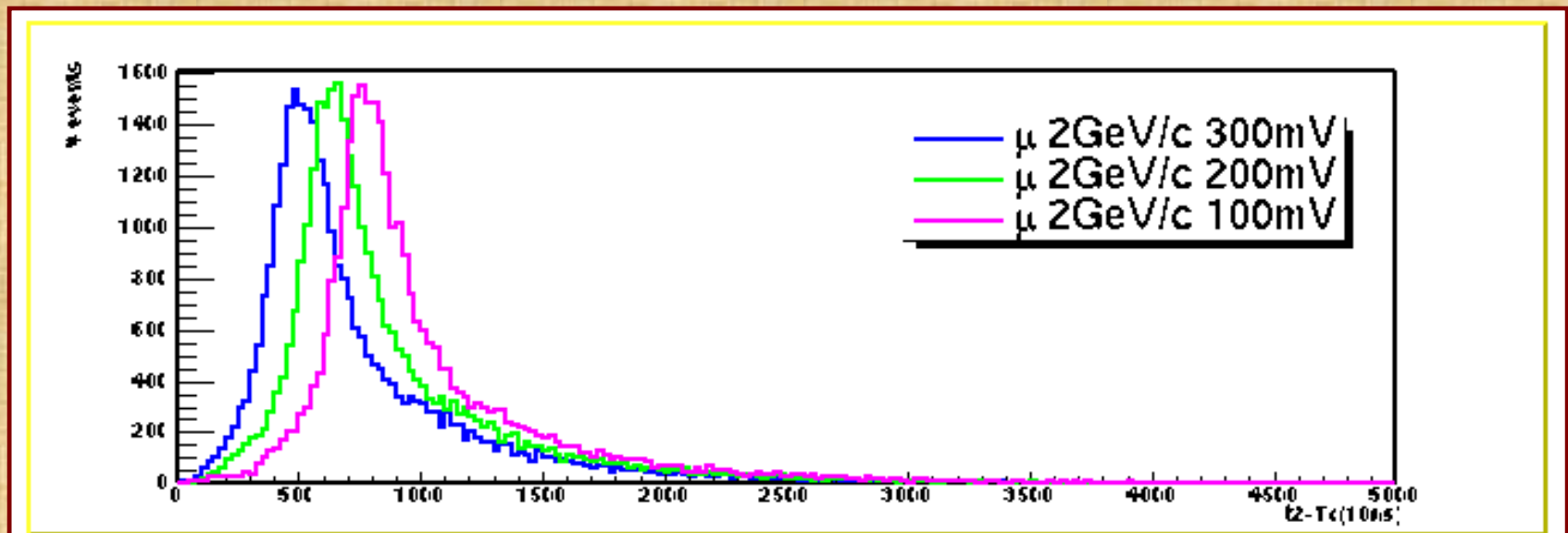
# Hit capture efficiency: threshold study

- The hit capture efficiency has been studied as a function of  $V_{th}$  (100mV, 200mV and 300mV);
- A sample of 2GeV/c muons and 2GeV/c gamma, crossing the tower orthogonally has been simulated;

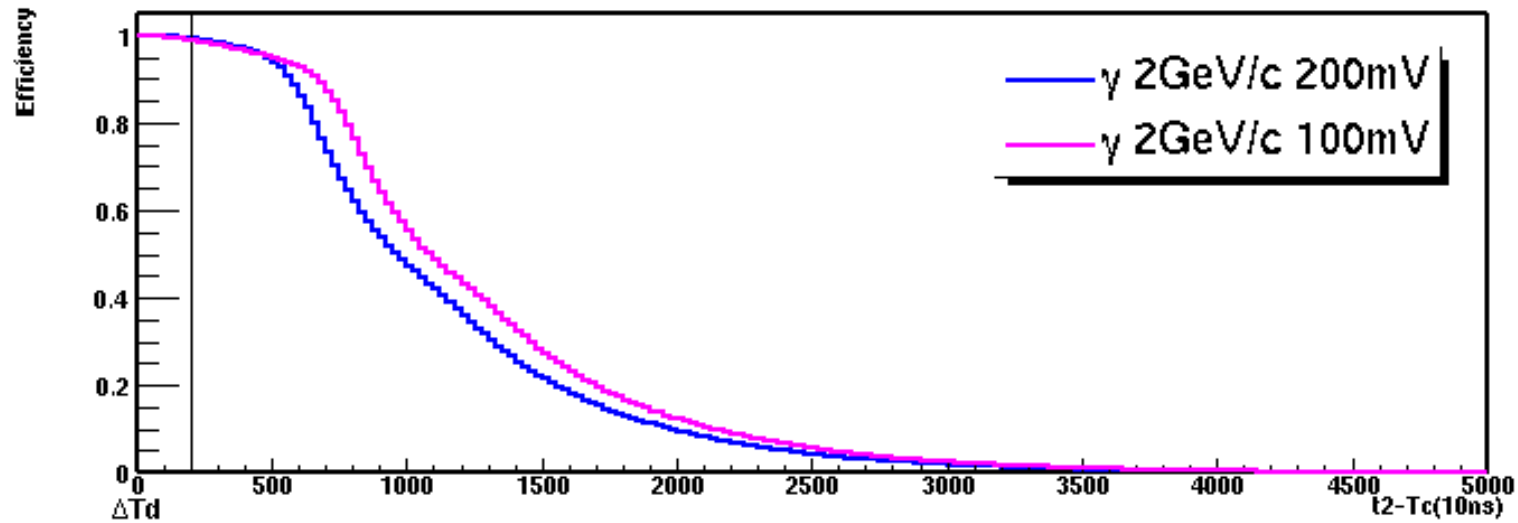
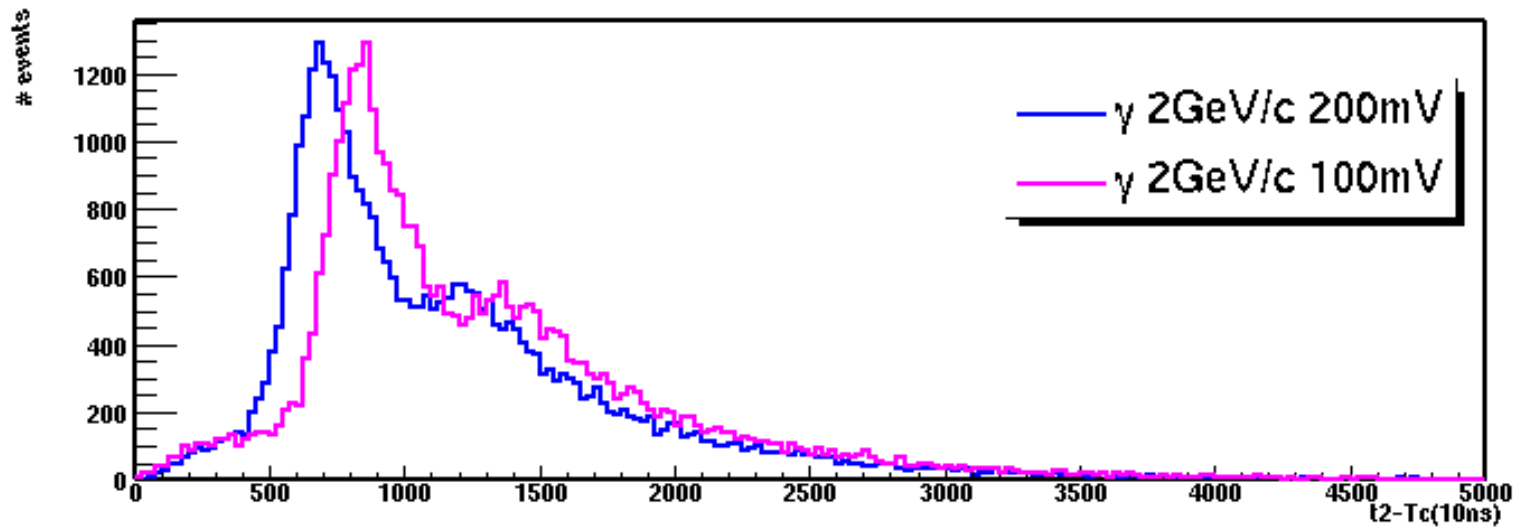
## Motivation:

- the SSD noise increases with the temperature
- the threshold could be consequently tuned  
(see S.Rainò talk)

# Efficiency vs $V_{th}$ (muons)



# Efficiency vs $V_{th}$ (gamma)



# Conclusions

- The TKR digit simulation has been used to study the tracker behavior
- A simulation of L1 trigger has been developed and a complete hit capture efficiency study performed
- The efficiency is not very dependent from the gamma energy, but ....  
.... the efficiency slightly decreases as the threshold increases.